Notice of References Cited Application/Control No. 10/075,285 Examiner Amare Mengistu Applicant(s)/Patent Under Reexamination LEE ET AL. Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2005/0253832 A1	11-2005	Chung, Kyu-Young	345/204
*	В	US-2004/0196232 A1	10-2004	Kim et al.	345/089
*	C	US-2003/0227433 A1	12-2003	Moon, Seung-Hwan	345/100
*	D	US-2002/0163488 A1	11-2002	Song et al.	345/87
*	E	US-6,421,038 B1	07-2002	Lee, Hyun Chang	345/98
	F	US-			
	G	US-			
	н	US-			
	_	US-			•
	J	US-			
	К	US-			
	٦	US-			:
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N						
	0						
	Р					:	
	Q					:	
	R					: :	
	s					: :	
	Т					:	

NON-PATENT DOCUMENTS

*	Γ	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	:	:	
	U			:	
	v				
	w		:	:	
	х		:	:	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.